Fitting a plane with arbitrary observational uncertainties

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In this note, I'll describe a method for inferring a planar relationship between three variables given a set of noisy (and possibly non-Gaussian) observations of a set of systems. For specificity, consider the problem of gyrochronology: there is postulated to be a linear relationship between the (true) age A_n of a star n and its (true) effective temperature T_n and rotational period P_n

$$\log A_n = m_0 + m_1 \log T_n + m_2 \log P_n . {1}$$

We would like to determine the best-fit value (or sample the posterior probability) of the parameter vector $m = \{m_0, m_1, m_2\}$ conditioned on a set of noisy observations \hat{A}_n , \hat{T}_n , and \hat{P}_n .

For this purpose, we need to compute the marginalized likelihood

$$p(\{\hat{A}_n, \hat{T}_n, \hat{P}_n\} \mid m) = \prod_{n=1}^{N} \int p(\hat{A}_n, \hat{T}_n, \hat{P}_n, A_n, T_n, P_n \mid m) \, dA_n \, dT_n \, dP_n \quad . \tag{2}$$

This joint probability function is shown in figure 1 and this factorization can be written as

$$p(\hat{A}_n, \hat{T}_n, \hat{P}_n, A_n, T_n, P_n \mid m) = p(T_n) p(P_n) p(A_n \mid T_n, P_n, m) p(\hat{A}_n \mid A_n) p(\hat{T}_n \mid T_n) p(\hat{P}_n \mid P_n)$$
where (by equation 1)

$$p(A_n | T_n, P_n, m) = \delta \left[\log A_n - (m_0 + m_1 \log T_n + m_2 \log P_n) \right] . \tag{3}$$

Now, let's say that we have J_n posterior samples

$$T_n^{(j)} \sim p(T_n | \hat{T}_n)$$

 $P_n^{(j)} \sim p(P_n | \hat{P}_n)$ (4)

and that we can evaluate $p(\hat{A}_n | A_n)$ up to a normalization constant. If you don't have the posterior samples, generate them from the uncertainties provided in the catalog and if you

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don't have functional form for the age likelihood, make one up using a KDE or similar. Now, we can evaluate the marginalized likelihood for a single star very efficiently as follows

$$p(\hat{A}_{n}, \hat{T}_{n}, \hat{P}_{n} | m) = \int p(T_{n}) p(P_{n}) p(A_{n} | T_{n}, P_{n}, m) p(\hat{A}_{n} | A_{n}) p(\hat{T}_{n} | T_{n}) p(\hat{P}_{n} | P_{n}) dA_{n} dT_{n} dP_{n}$$

$$\propto \int p(A_{n} | T_{n}, P_{n}, m) p(\hat{A}_{n} | A_{n}) p(T_{n} | \hat{T}_{n}) p(P_{n} | \hat{P}_{n}) dA_{n} dT_{n} dP_{n}$$

$$\approx \frac{1}{J_{n}} \sum_{j=1}^{J_{n}} p(\hat{A}_{n} | A_{n}^{(j)})$$
(5)

where $A_n^{(j)}$ is computed from the posterior samples using equation 1.

Finally, the full marginalized log-likelihood is

$$\log p(\{\hat{A}_n, \hat{T}_n, \hat{P}_n\} \mid m) \approx \log \mathcal{Z} + \sum_{n=1}^{N} \log \left[\sum_{j=1}^{J_n} p(\hat{A}_n \mid A_n^{(j)}) \right]$$
 (6)

where \mathcal{Z} is an irrelevant normalization constant. You can then toss this into an optimizer and find the maximum likelihood plane or assert a prior p(m) and draw posterior samples.

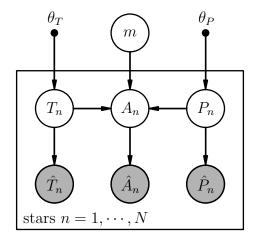


Fig. 1.—